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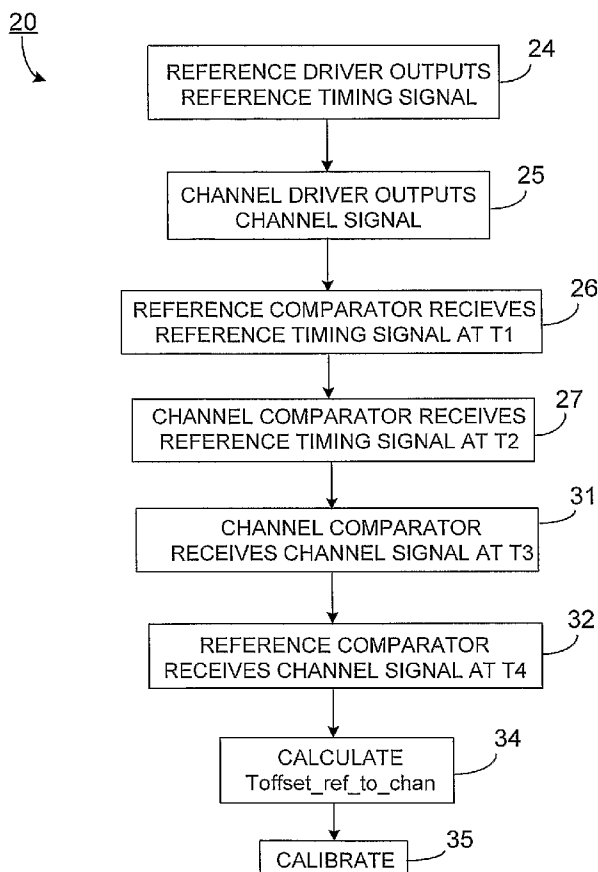
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(54) Title: CALIBRATING AUTOMATIC TEST EQUIPMENT



(57) Abstract: Calibrating automatic test equipment (ATE) includes determining an offset between a reference timing event and a channel event, where the channel event is associated with a communication channel of the ATE, and adjusting signal transmission over the communication channel based on the offset. Determining the offset may include obtaining a first time at which a reference timing signal is received at a device associated with a reference timing source, obtaining a second time at which the reference timing signal is received at a device associated with the communication channel, obtaining a third time at which a channel signal is received at the device associated with the communication channel, obtaining a fourth time at which the channel signal is received at the device associated with the reference timing source, and calculating the offset using the first time, the second time, the third time, and the fourth time.



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